

## **Quarterly Reliability Monitoring Results**

## Quarters: Q1/2022 to Q4/2023

Based on structural similarity

Supplier Nexperia B.V. Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test		User Part Number						
		BAV23-Q						
		Part Description						
		Nexperia DHAM Small Signal Bipolar Diode						
		SMD package						
		Test Conditions	Duration	# Lots	# Quantity	# Rejects		
	TEST							
	Pre- and Post-Stress							
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below		
		JESD22-A113						
		Bake Tamb = 125 °C	24 hours					
	PC	Soak Tamb = 85 °C, RH = 85%	168 hours					
# A1	Preconditioning	Reflow soldering	3 cycles	1514	64430	0		
		MIL-STD-750-1						
	HTRB	M1038 Method A						
		Tj = Tjmax, Vr = 100% of max. datasheet						
# B1	Bias	reverse voltage	1000 hours	110	4920	0		
	TC	JESD22-A104				_		
# A4	Temperature Cycling	-65 °C to Tjmax, not to exceed 150°C	1000 cycles	311	14080	0		
	UHAST	JECD22 4110						
# A3 <b>or</b>	Unbiased HAST	JESD22-A118 Tamb = 130 °C, RH = 85 %						
# A3 <b>01</b>	Olibiaseu HAST	· · · · · · · · · · · · · · · · · · ·	- 96 hours	311	14080	0		
	AC	JESD22-A102						
# 42 alt	AC Autoclave	Tamb = 121 °C, RH = 100 % Pressure = 205 kPa (29.7 psia)						
# A3 alt	Autociave	riessuie – 203 kra (29.7 psia)						
	H3TRB	JESD22-A101						
	High Humidity High	Tamb = 85 °C, RH = 85%, VR = 80 % of						
# A2 alt	Temperature Reverse Bias		1000 hours	311	14080	0		
# AZ ait	. cperature Reverse Dias	MIL-STD-750 Method 1037	1000 110015	211	14000	U		
	IOL	ton = toff, devices powered to insure $\Delta T_i$ =						
# A5	Intermittent Operating Life		1000 hours	312	14120	0		
# NJ	The fine control operating Life	100 0 101 15000 070105	1000 110013	J12	17120	0		
	RSH	JESD22-A111						
# C8	Resistance to Solder Heat		10 s	269	8070	0		
50	SD		200	203	3070			
# C10	Solderability	J-STD-002		222	6660	0		
. 010					5000	-		

<sup>[1]</sup> The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

## **Calculation of FIT and MTTF**

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1)
Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia					
DHAM	Small Signal Bipolar Diode	4920	0	0,86	1,16E+09

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